


<b>Search Notes</b> 	<b>Application/Control No.</b> 09925397	<b>Applicant(s)/Patent Under Reexamination</b> CHANG ET AL.
	<b>Examiner</b> Ehichioya, Fred I	<b>Art Unit</b> 2162

### SEARCHED

Class	Subclass	Date	Examiner
707	2, 3, 5, 10, 104.1	6/8/2009	FE
709	224	6/8/2009	FE

### SEARCH NOTES

Search Notes	Date	Examiner
IEEE Xplore	12/16/07	FE
East (US-PG Pub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE
East (US-PG Pub, USPat, EPO, JPO, Derwent).text search only	6/24/08	FE
Google.com	6/24/08	FE
East (US-PG Pub, USPat, EPO, JPO, Derwent).text search only	2/23/2009	FE
Google Search	2/20/2009	FE
Consulted with Tod Swann (TQAS)	6/1/2009	FE
East (US-PG Pub, USPat, EPO, JPO, Derwent).inventor name search, class/subclass and text search	6/8/2009	FE
NPL Multi-Search (ACM, IEEE, INSPEC, ProQuest ... )	6/8/2009	FE
Google Patent Search	6/8/2009	FE

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
707	104.1	6/8/2009	FE
709	224	6/8/2009	FE

/FRED I EHICHIOYA/  
Examiner, Art Unit 2156